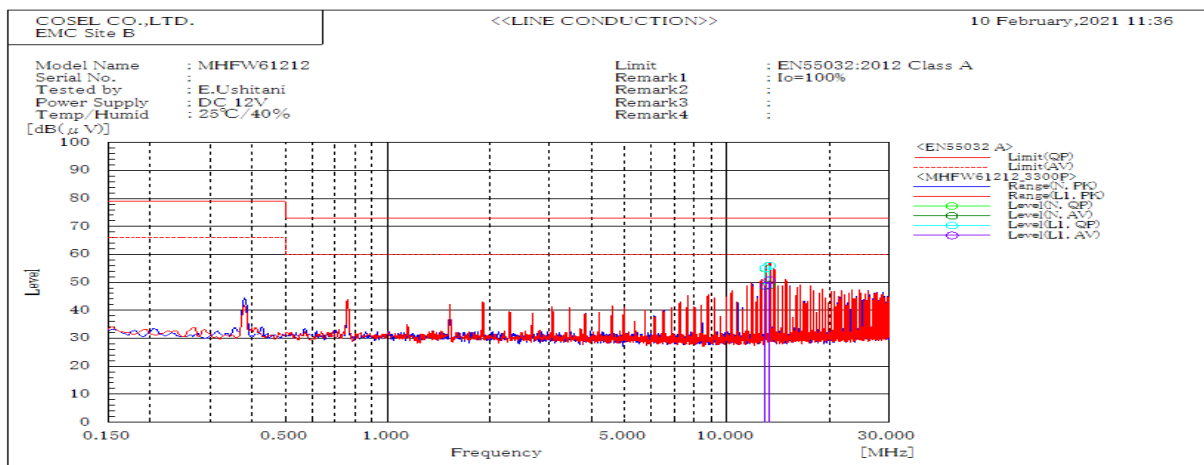
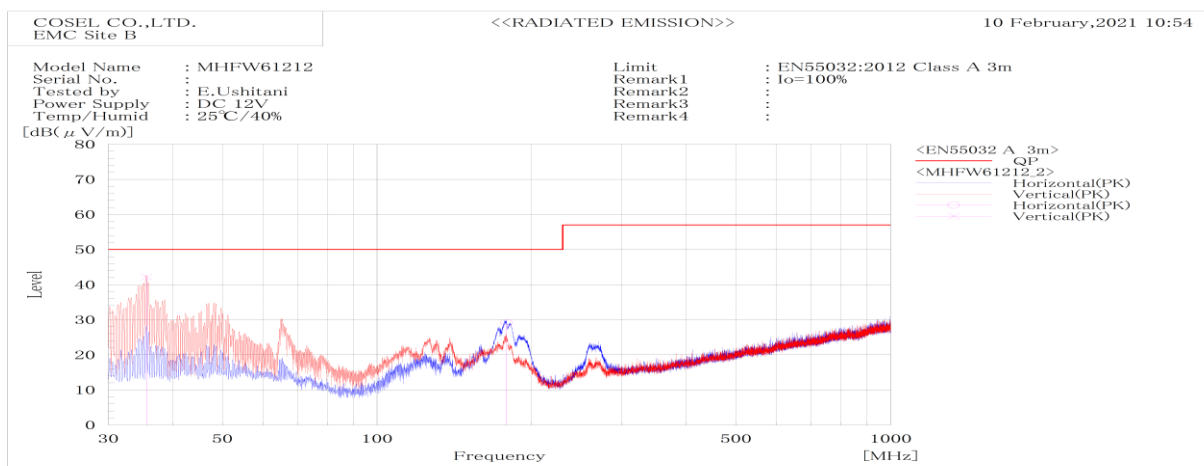


DATA SHEET		Date	05-Nov-21
Model	MHFW61212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



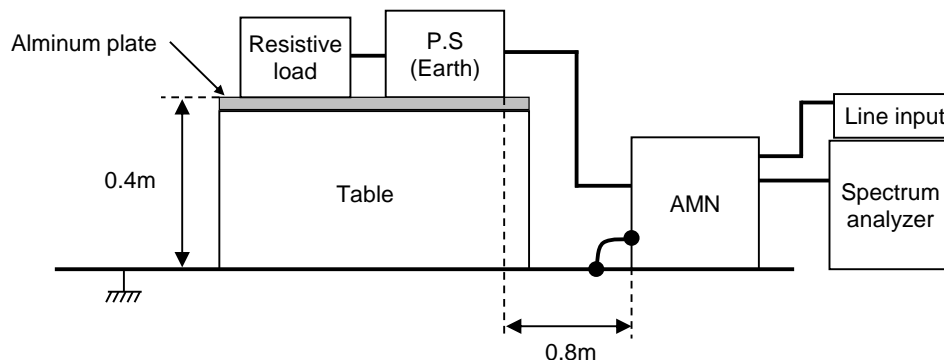
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
13.358	L1	56.1	50.7	73	60	16.9	9.3	Pass	
12.978	L1	55.2	48.8	73	60	17.8	11.2	Pass	
13.358	N	55.9	49.1	73	60	17.1	10.9	Pass	
12.973	N	55	48.6	73	60	18	11.4	Pass	



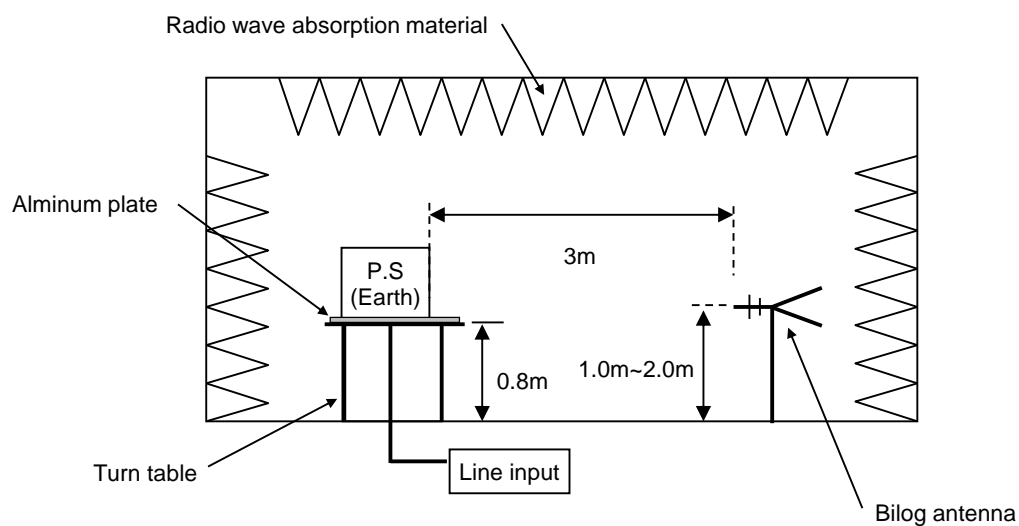
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
178.692	H	Stable	29.1	50	20.9	Pass	196.6	153.2	
35.584	V	Stable	42.2	50	7.8	Pass	100.2	36.2	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission



Conditions

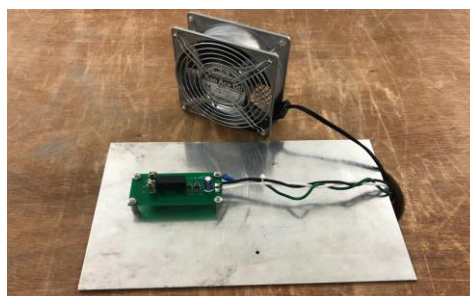
Test : EMI
Model Name: MHFW6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

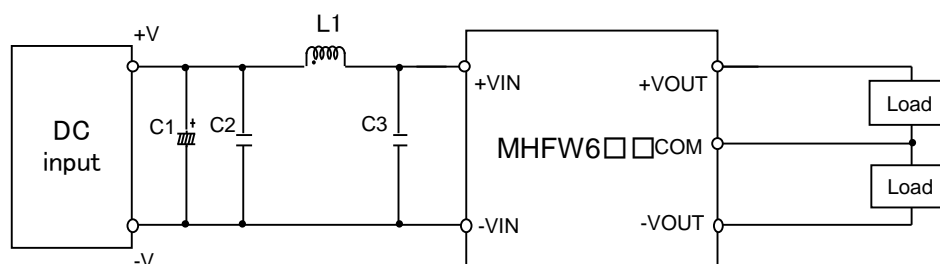


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)